Electronic Supplementary Information

Screw-Dislocation-Driven *t*-Ba₂V₂O₇ Helical Meso/Nanosquares: Microwave Irradiation Assisted-SDBS Fabrication and Their Unique Magnetic Properties

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Figure S1. (a) Observed (black crosses) and calculated (red line) X-ray powder diffraction patterns of t-Ba₂V₂O₇ spiral-like microsquares (sample S1) revealed from simultaneous GSAS refinement analysis. The differences between the experimental and refined patterns are represented by the blue solid line at the bottom. The inset shows the crystal structure of t-Ba₂V₂O₇ viewed along [010]. (b) Typical SEM images of helical t-Ba₂V₂O₇ materials.

Data	a (Å)	<i>b</i> (Å)	<i>c</i> (Å)	α°	β°	γ°	R _{wp} *	R _p *
Refined data	13.684	7.260	7.494	89.19	100.62	88.04	0.2057	0.1571
PDF No. 76-612	13.571	7.320	7.306	90.09	99.48	87.32		

Table S1 Cell parameters of *t*-Ba₂V₂O₇ from refinement results of GSAS program compared with standard data.

Note: * R_{wp}: Reliability factor; R_p: Profile R-factor. (R_{wp} and R_p are defined in reference ^[1].)



Figure S2. TEM and HRTEM images of t-Ba₂V₂O₇ helix mesostructures (sample S4), which is synthesized by microwave irradiation process via reacting for 30min. From the Figure, screw nanospheres are absorbed onto the outer surface of layered nanosquares, and control the preferential growth along 2D direction of interlaced dislocation growth.



Figure S3. Magnetization curves of screw dislocated nanospheres t-Ba₂V₂O₇ (Sample S3, prepared via microwave irradiation for 2 min) as a function of the testing temperatures.



Figure S4. M–H curve of t-Ba₂V₂O₇ nanospheres (Sample S4, obtained by the microwave irradiation for 30 min), illustrating the magnetic properties.

Sample	Valence	V ⁵⁺		V ⁴⁺		V ⁵⁺ _{2P1/2} / V ⁴⁺ _{2P1/2} ratio	
		V 2P3/2	V 2P1/2	V _{2P3/2}	V _{2P1/2}		
	Bindingenergy(Standard value)	517.6		516.3			
XPS Sample 2	Binding energy	512.43	519.68	509.09	518.57		
	FWHM (eV)	0.6110	3.1951	4.9914	5.0000		
	Molar fraction (%)	0.40	72.84	14.14	12.63	5.76722	

Table S2 The Results f peak fitting for XPS peaks of $Ba_2V_2O_7$ micro/nanosquares

Reference:

[1] Toby, B. H. EXPGUI, a graphical user interface for GSAS. J. Appl. Cryst. 2001, 34, 210-213.